

<b>Notice of References Cited</b>	Application/Control No. 10/197,651	Applicant(s)/Patent Under Reexamination GAJDA, MARK A.	
	Examiner Walter L. Lindsay, Jr.	Art Unit 2812	Page 1 of 1

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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Sheet 1 of 1

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE		Atty. Docket No. GB 010121		Serial No. 10/197,651	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		Applicant MARK A. GAJDA			
		Filing 7/17/02		Group 2812	

  

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Ex. Int.		Document Number								Date	Name	Class	Sub-class	Filing Date If Approp.
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	AE													
	AF													

  

FOREIGN PATENT DOCUMENTS																
		Document Number								Date	Country	Class	Sub-class	Trans.		
															Yes	No
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Examiner <i>WLL</i> <i>[Signature]</i>	Date Considered <i>9/03/03</i>
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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Applicant Mark A. GAJDA		Filing Date CONCURRENTLY	
				Group			

10/19/03  
 10/17/03

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